

**Search Notes**

Application/Control No.

10/715,464

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

TAKABAYASHI ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	updated	3/2/2006	SWH
427	updated	3/2/2006	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPGPUB text search (see attached)	3/2/2006	SWH